

MITSUBISHI <DIGITAL ASSP>
M74HC534-1P/FP

OCTAL 3-STATE INVERTING D-TYPE FLIP-FLOP

DESCRIPTION

The M74HC534-1 is an integrated circuit chip consisting of eight edge-triggered 3-state output D-type flip-flops with common clock input and output-enable input.

FEATURES

- High-fanout 3-state output : ($I_{OL}=24\text{mA}$, $I_{OH}=-24\text{mA}$)
- High-speed : (Clock frequency) 80MHz typ.
($C_L=50\text{pF}$, $V_{CC}=5\text{V}$)
- Low power dissipation : 25 μW /package, max
($V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$, quiescent state)
- High noise margin : 30% of V_{CC} , min ($V_{CC}=4.5, 6\text{V}$)
- Capable of driving 60 74LS TTL loads
- Wide operating voltage range : $V_{CC}=2\sim 6\text{V}$
- Wide operating temperature range : $T_a=-40\sim +85^\circ\text{C}$

APPLICATION

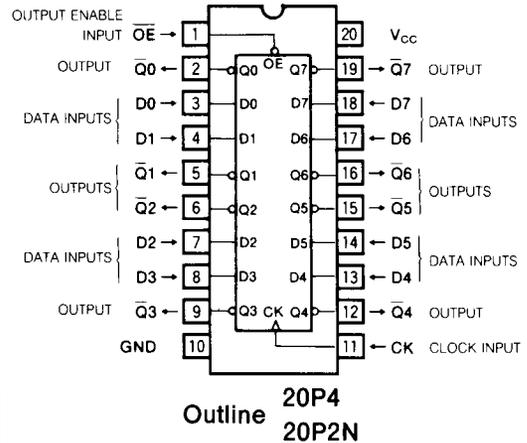
General purpose, for use in industrial and consumer digital equipment.

FUNCTION

Use of silicon gate technology allows the M74HC534-1 to maintain the low power dissipation and high noise margin characteristics of the standard CMOS logic 4000B series while giving high-speed performance equivalent to the 74LS534. The circuit is designed to suppress the increased switching noise that normally occurs at high output currents. The M74HC534-1 consists of eight edge-triggered D-type flip-flops, sharing common clock input CK and output-enable input OE.

When CK changes from low-level to high-level, the signals just previously data input D is stored in the flip-flop.

PIN CONFIGURATION (TOP VIEW)

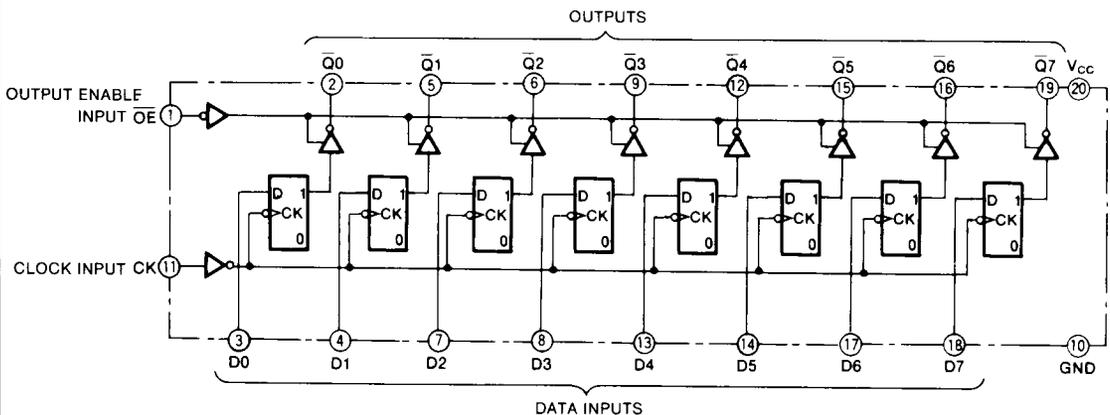


When \overline{OE} is low-level, the signal stored in the flip-flop will be output to \overline{Q} .

When \overline{OE} is high-level, all outputs \overline{Q} will become high impedance state. The contents stored in the flip-flop will not be affected even if \overline{OE} changes.

A version of the M74HC534-1 with the same pin connection and a noninverted output, the M74HC374-1, is also available.

LOGICAL DIAGRAM



OCTAL 3-STATE INVERTING D-TYPE FLIP-FLOP

FUNCTION TABLE (Note 1)

Inputs			Output
OE	CK	D	Q
L	↑	L	H
L	↑	H	L
L	L	X	Q ⁰
L	H	X	Q ⁰
L	↓	X	Q ⁰
H	X	X	Z

Note 1 : Q⁰ : Output state Q before CK changed.
 Z : High impedance
 X : Irrelevant
 ↑ : Change from low-to high-level
 ↓ : Change from high-to low-level

ABSOLUTE MAXIMUM RATINGS (T_a = -40~+85°C, unless otherwise noted)

Symbol	Parameter	Conditions	Ratings	Unit
V _{CC}	Supply voltage		-0.5~+7.0	V
V _I	Input voltage		-0.5~V _{CC} +0.5	V
V _O	Output voltage		-0.5~V _{CC} +0.5	V
I _{IK}	Input protection diode current	V _I < 0V	-20	mA
		V _I > V _{CC}	20	
I _{OK}	Output parasitic diode current	V _O < 0V	-20	mA
		V _O > V _{CC}	20	
I _O	Output current		±50	mA
I _{CC}	Supply/GND current	V _{CC} , GND	±200	mA
P _d	Power dissipation	(Note 2)	500	mW
T _{stg}	Storage temperature		-65~+150	°C

Note 2 : M74HC534-1FP : T_a = -40~+75°C and T_a = 75~85°C are derated at -7mW/°C

RECOMMENDED OPERATING CONDITIONS (T_a = -40~+85°C)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V _{CC}	Supply voltage	2		6	V
V _I	Input voltage	0		V _{CC}	V
V _O	Output voltage	0		V _{CC}	V
T _{opr}	Operating temperature	-40		+85	°C
t _r , t _f	Input rise time, fall time	V _{CC} = 2.0V		500	ns/V
		V _{CC} = 4.5V	0	50	
		V _{CC} = 6.0V	0	30	

ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits					Unit
			25°C		-40~+85°C			
			V _{CC} (V)	Min	Typ	Max	Min	
V _{IH}	High-level input voltage	V _O = 0.1V, V _{CC} = 0.1V I _O = 20μA	2.0	1.5			1.5	V
			4.5	3.15			3.15	
			6.0	4.2			4.2	
V _{IL}	Low-level input voltage	V _O = 0.1V, V _{CC} = 0.1V I _O = 20μA	2.0			0.5	0.5	V
			4.5			1.35	1.35	
			6.0			1.8	1.8	
V _{O_H}	High-level output voltage	V _I = V _{IL} , V _{IH}	I _{OH} = -20μA	2.0	1.9		1.9	V
			I _{OH} = -20μA	4.5	4.4		4.4	
			I _{OH} = -20μA	6.0	5.9		5.9	
			I _{OH} = -24mA	4.5	3.83		3.70	
V _{O_L}	Low-level output voltage	V _I = V _{IH} , V _{IL}	I _{OL} = 20μA	2.0		0.1	0.1	V
			I _{OL} = 20μA	4.5		0.1	0.1	
			I _{OL} = 20μA	6.0		0.1	0.1	
			I _{OL} = 24mA	4.5		0.44	0.53	
I _{IH}	High-level input current	V _I = 6V	6.0		0.1	1.0	μA	
I _{IL}	Low-level input current	V _I = 0V	6.0		-0.1	-1.0	μA	
I _{OZH}	Off-state high-level output current	V _I = V _{IH} , V _{IL} , V _O = V _{CC}	6.0		0.5	5.0	μA	
I _{OZL}	Off-state low-level output current	V _I = V _{IH} , V _{IL} , V _O = GND	6.0		-0.5	-5.0	μA	
I _{CC}	Quiescent supply current	V _I = V _{CC} , GND, I _O = 0μA	6.0		5.0	50.0	μA	

OCTAL 3-STATE INVERTING D-TYPE FLIP-FLOP

SWITCHING CHARACTERISTICS ($V_{CC} = 5V$, $T_a = 25^\circ C$)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
f_{max}	Maximum repetitive frequency		35			MHz
t_{TLH}	Low-to high-level and high-to low-level output transition time	$C_L = 50pF$ (Note 4)			10	ns
t_{THL}					10	ns
t_{PLH}					20	ns
t_{PHL}	Low-to high-level and high-to low-level output propagation time ($CK - \bar{Q}$)				20	ns
t_{PLZ}	Low-level and high-level output disable time ($\bar{OE} - \bar{Q}$)	$C_L = 5 pF$ (Note 4)			18	ns
t_{PHZ}					18	ns
t_{PZL}	Low-level and high-level output enable time ($\bar{OE} - \bar{Q}$)	$C_L = 50pF$ (Note 4)			20	ns
t_{PZH}					20	ns

SWITCHING CHARACTERISTICS ($V_{CC} = 2\sim 6V$, $T_a = -40\sim +85^\circ C$)

Symbol	Parameter	Test conditions	Limits						Unit
			25°C			-40~+85°C			
			$V_{CC}(V)$	Min	Typ	Max	Min	Max	
f_{max}	Maximum repetitive frequency	$C_L = 50pF$ (Note 4)	2.0	6			5		MHz
			4.5	32			26		
			6.0	38			31		
t_{TLH}	Low-to high-level and high-to low-level output transition time	$C_L = 50pF$ (Note 4)	2.0		13	60		75	ns
			4.5		5	12		15	
			6.0		4	10		13	
t_{THL}	Low-to high-level and high-to low-level output transition time	$C_L = 50pF$ (Note 4)	2.0		16	60		75	ns
			4.5		5	12		15	
			6.0		4	10		13	
t_{PLH}	Low-to high-level and high-to low-level output propagation time ($CK - \bar{Q}$)	$C_L = 50pF$ (Note 4)	2.0		35	105		130	ns
			4.5		12	21		26	
			6.0		10	18		22	
t_{PHL}	Low-to high-level and high-to low-level output propagation time ($CK - \bar{Q}$)	$C_L = 50pF$ (Note 4)	2.0		34	105		130	ns
			4.5		13	21		26	
			6.0		10	18		22	
t_{PLZ}	Low-level and high-level output disable time ($\bar{OE} - \bar{Q}$)	$C_L = 50pF$ (Note 4)	2.0		16	105		130	ns
			4.5		8	21		26	
			6.0		7	18		22	
t_{PHZ}	Low-level and high-level output disable time ($\bar{OE} - \bar{Q}$)	$C_L = 50pF$ (Note 4)	2.0		17	105		130	ns
			4.5		10	21		26	
			6.0		10	18		22	
t_{PZL}	Low-level and high-level output enable time ($\bar{OE} - \bar{Q}$)	$C_L = 50pF$ (Note 4)	2.0		22	105		130	ns
			4.5		8	21		26	
			6.0		7	18		22	
t_{PZH}	Low-level and high-level output enable time ($\bar{OE} - \bar{Q}$)	$C_L = 50pF$ (Note 4)	2.0		27	105		130	ns
			4.5		11	21		26	
			6.0		9	18		22	
C_I	Input capacitance						10	pF	
C_O	Off-state output capacitance	$\bar{OE} = V_{CC}$					15	pF	
C_{PD}	Power dissipation capacitance (Note 3)			61.6				pF	

Note 3 : C_{PD} is the internal capacitance of the IC calculated from operation supply current under no-load conditions (per flip-flop). The power dissipated during operation under no-load condition is calculated using the following formula :

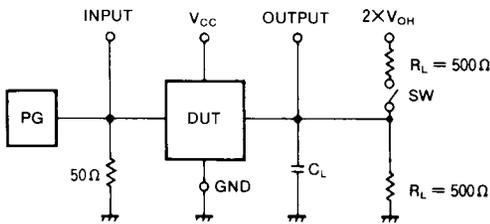
$$P_D = C_{PD} \cdot V_{CC}^2 \cdot f_1 + I_{CC} \cdot V_{CC}$$

OCTAL 3-STATE INVERTING D-TYPE FLIP-FLOP

TIMING REQUIREMENTS ($V_{CC} = 2\sim 6V$, $T_a = -40\sim +85^\circ C$)

Symbol	Parameter	Test conditions	Limits						Unit
			25°C			-40~+85°C			
			$V_{CC}(V)$	Min	Typ	Max	Min	Max	
t_w	Clock pulse width		2.0	60	10		75		ns
			4.5	12	3		15		
			6.0	10	2		13		
t_{su}	D setup time with respect to CK		2.0	50	2		65		ns
			4.5	10	1		13		
			6.0	9	0		11		
t_h	D hold time with respect to CK		2.0	25	1		30		ns
			4.5	5	1		6		
			6.0	5	0		6		

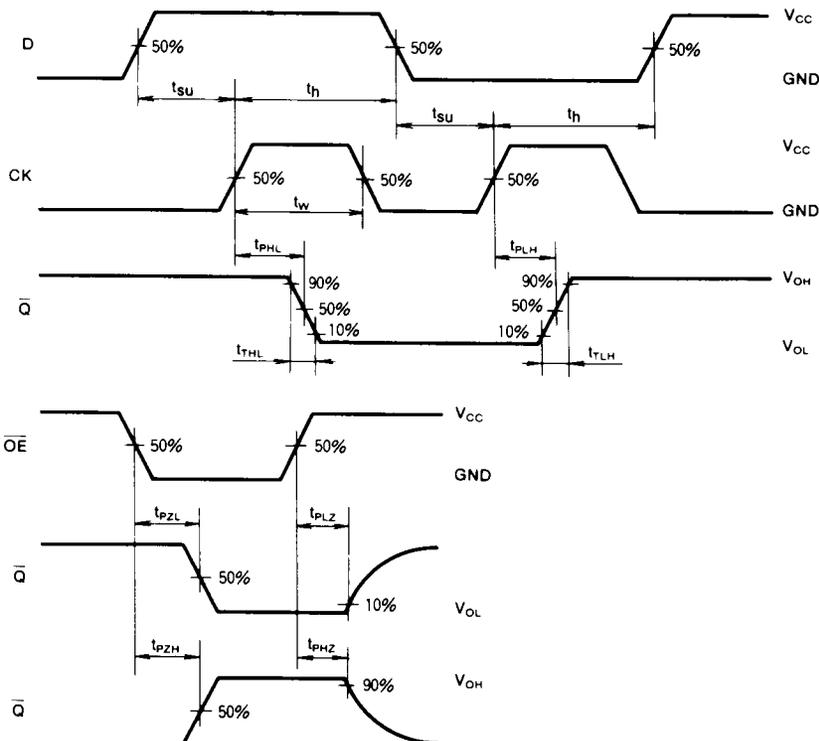
Note 4 : Test Circuit



Parameter	SW
t_{TLH}, t_{THL}	Open
t_{PLH}, t_{PHL}	Open
t_{PLZ}	Closed
t_{PHZ}	Open
t_{PZL}	Closed
t_{PZH}	Open

- (1) The pulse generator (PG) has the following characteristics (10%~90%) : $t_r=3ns$, $t_f=3ns$
- (2) The capacitance C_L includes stray wiring capacitance and the probe input capacitance.

TIMING DIAGRAM



**MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES**

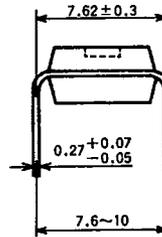
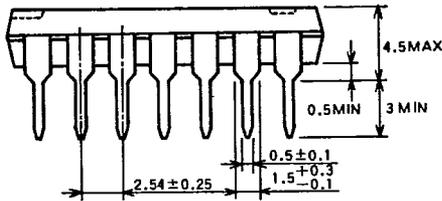
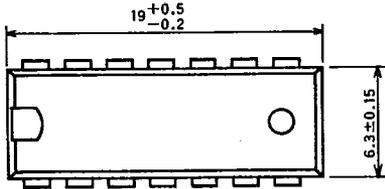
6249827 MITSUBISHI (DGTL LOGIC)

91D 12849

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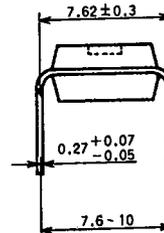
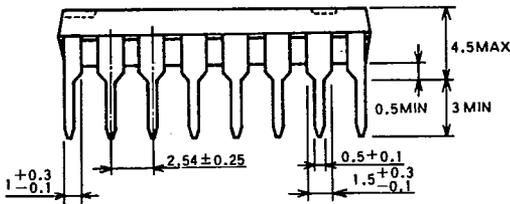
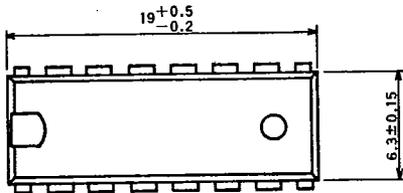
TYPE 14P4 14-PIN MOLDED PLASTIC DIP

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIP

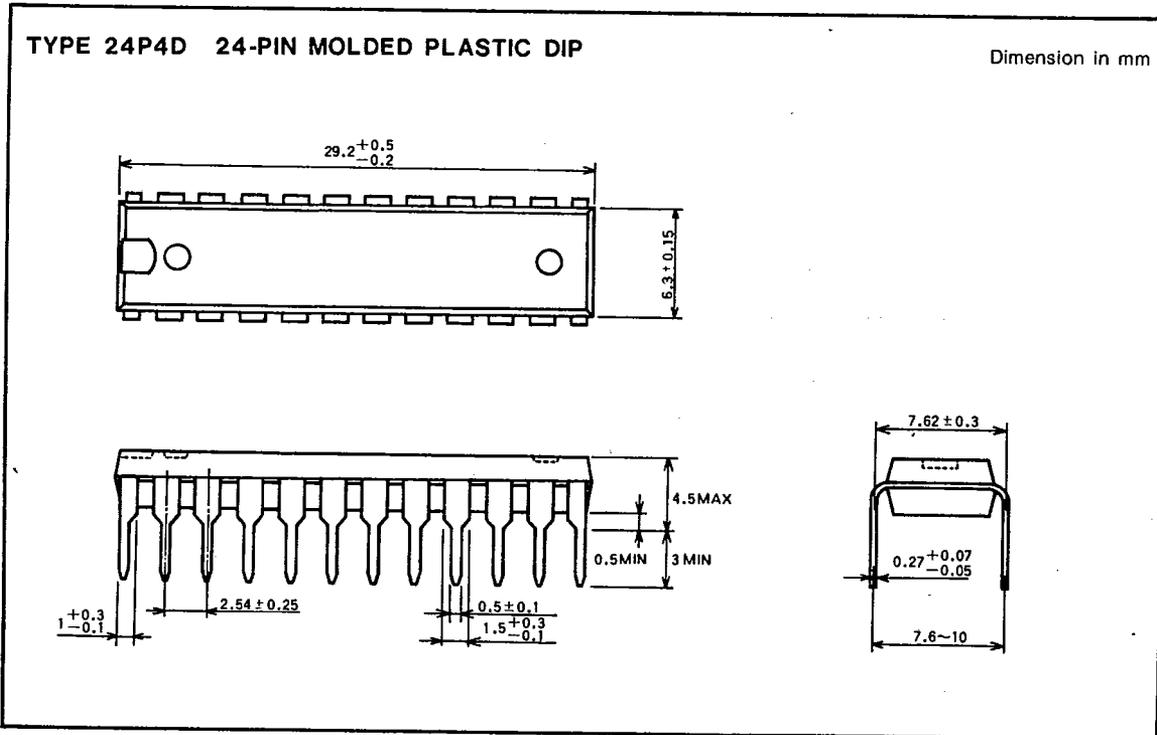
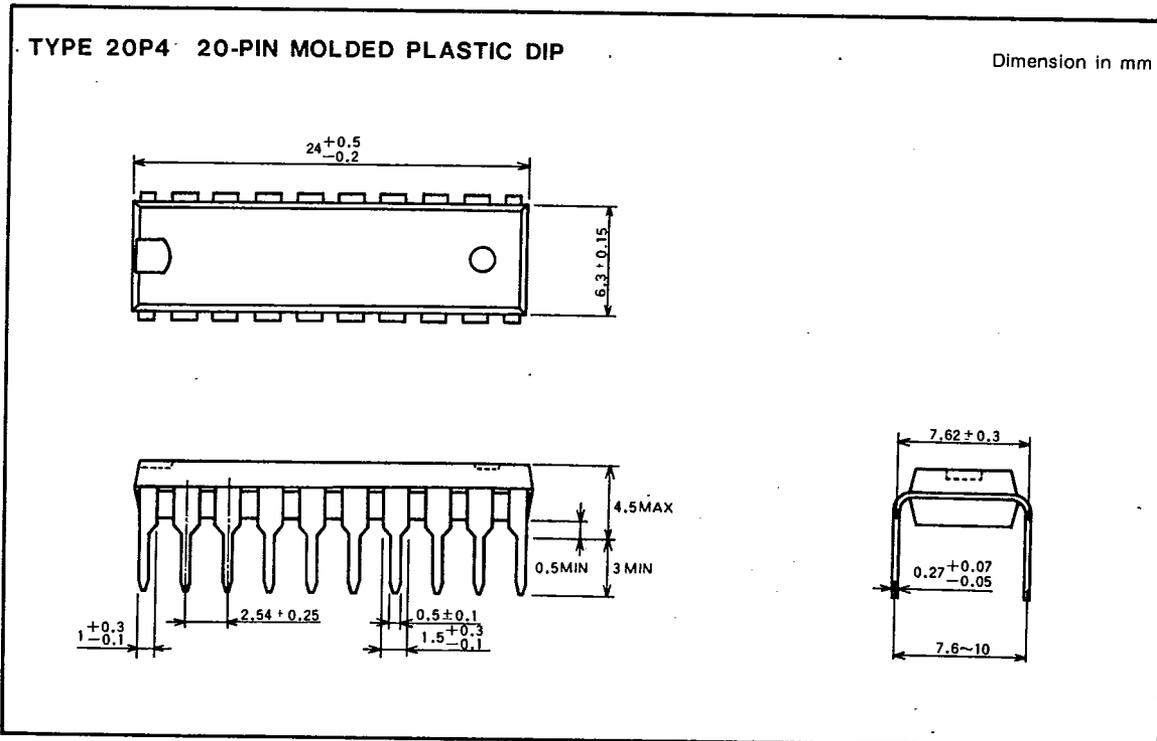
Dimension in mm



MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

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91D 12850 D.T-90-20



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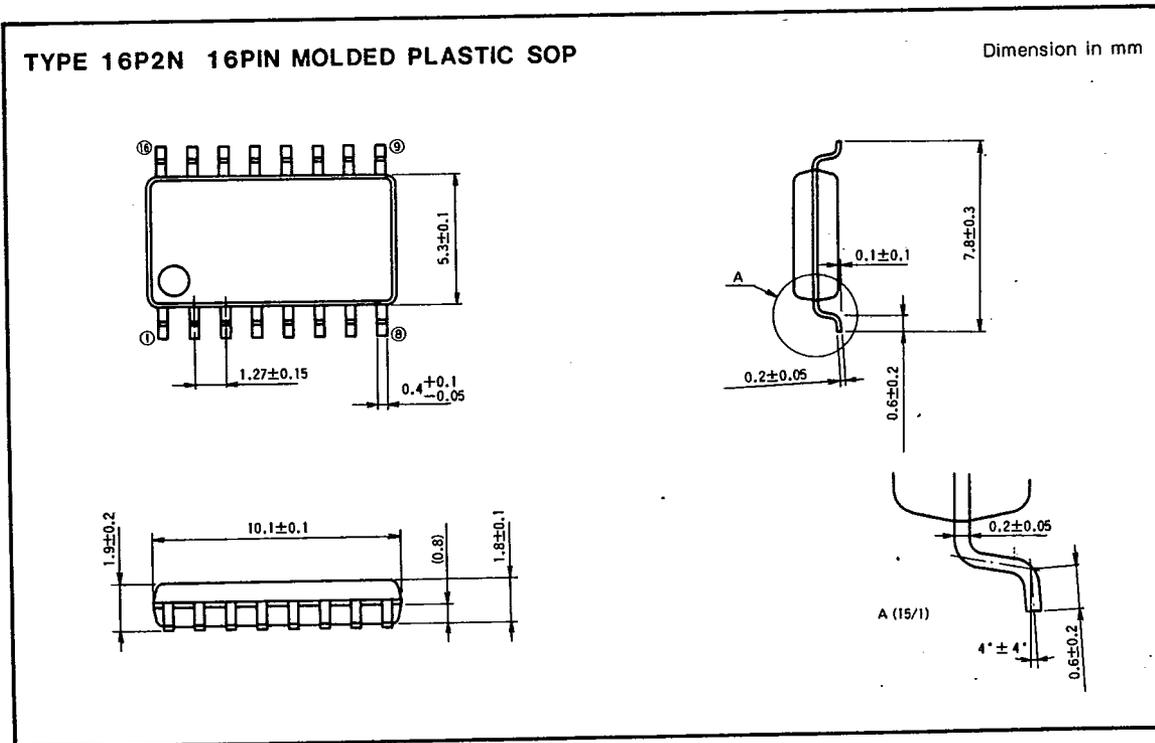
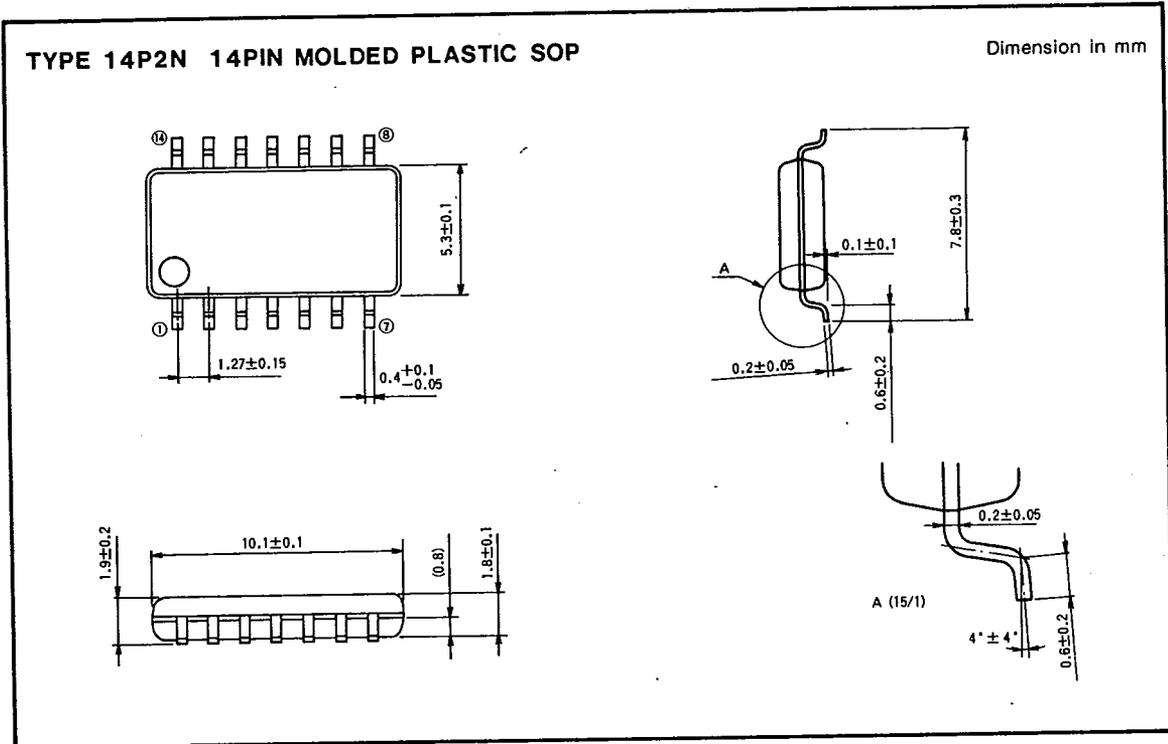


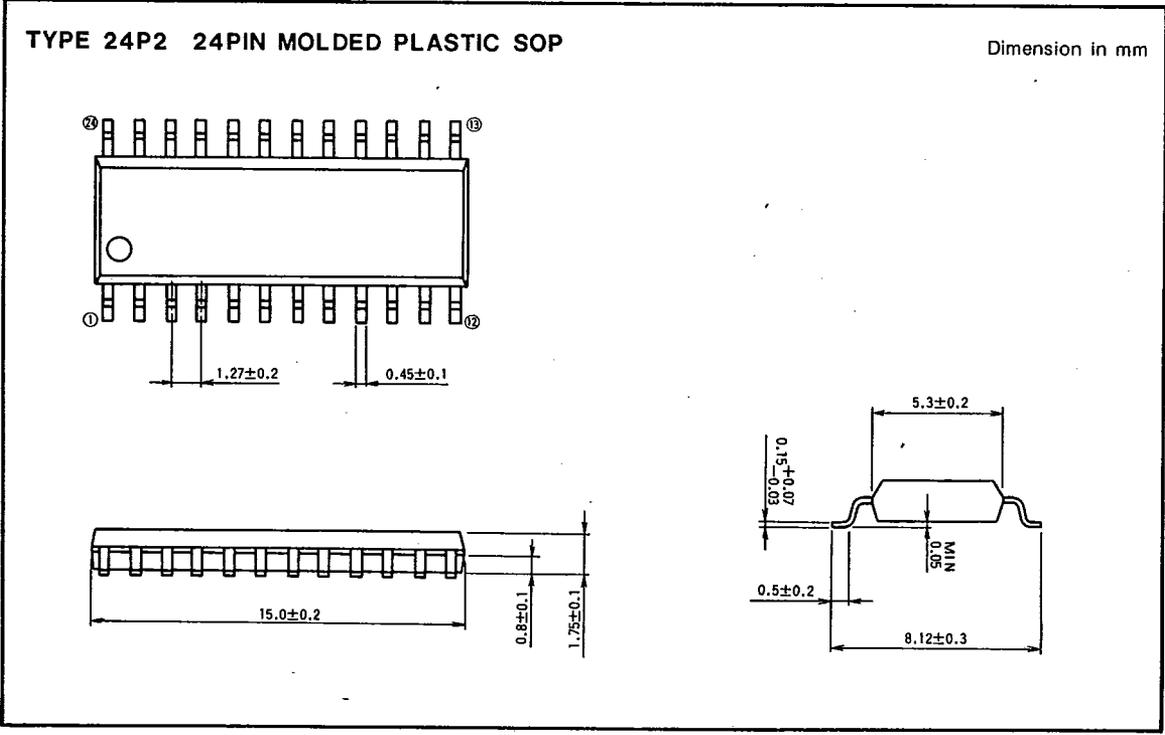
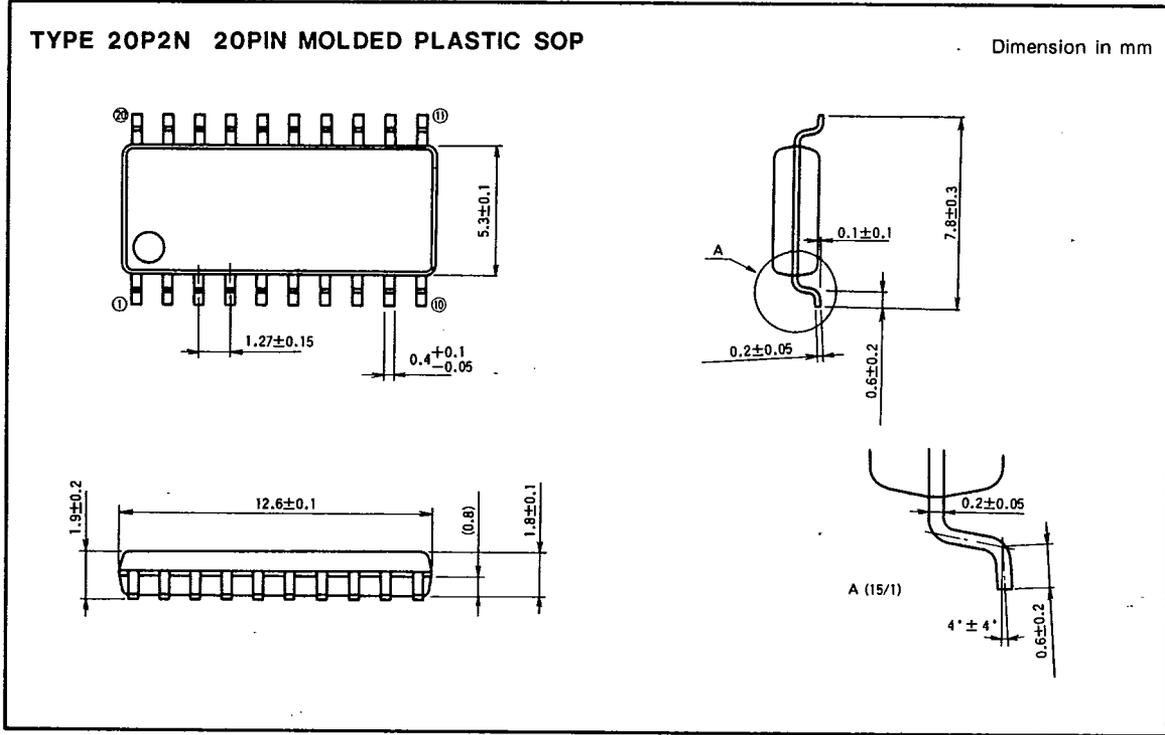
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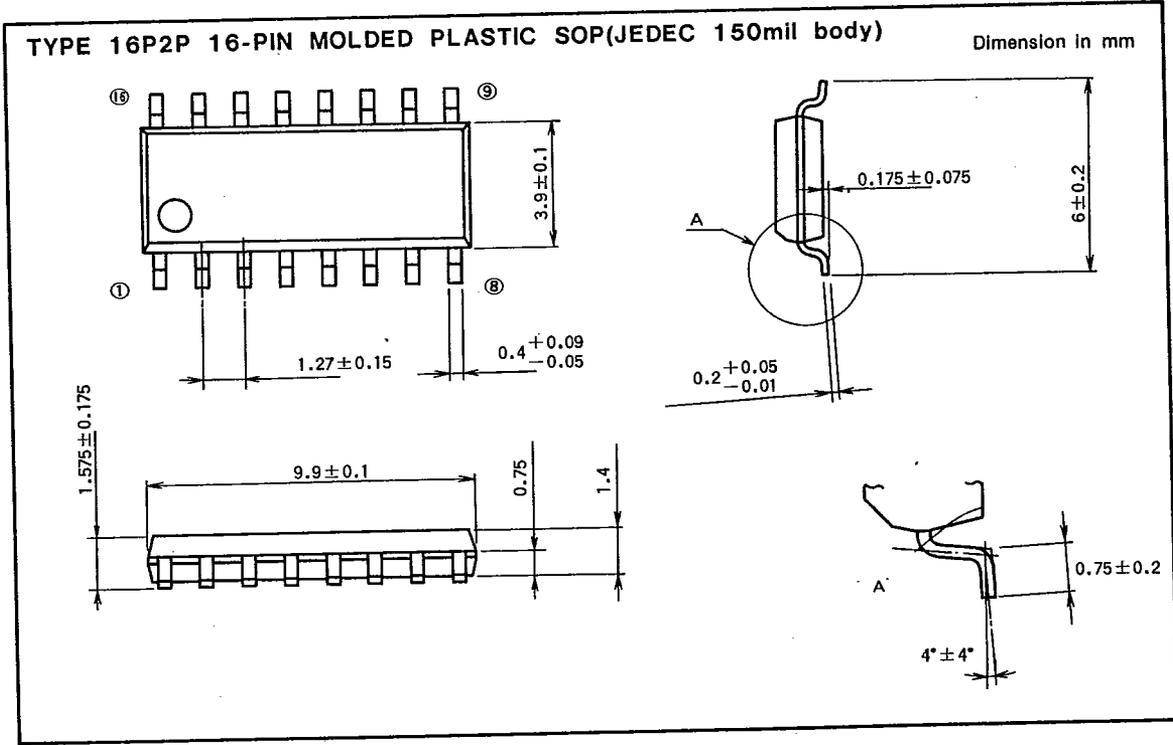
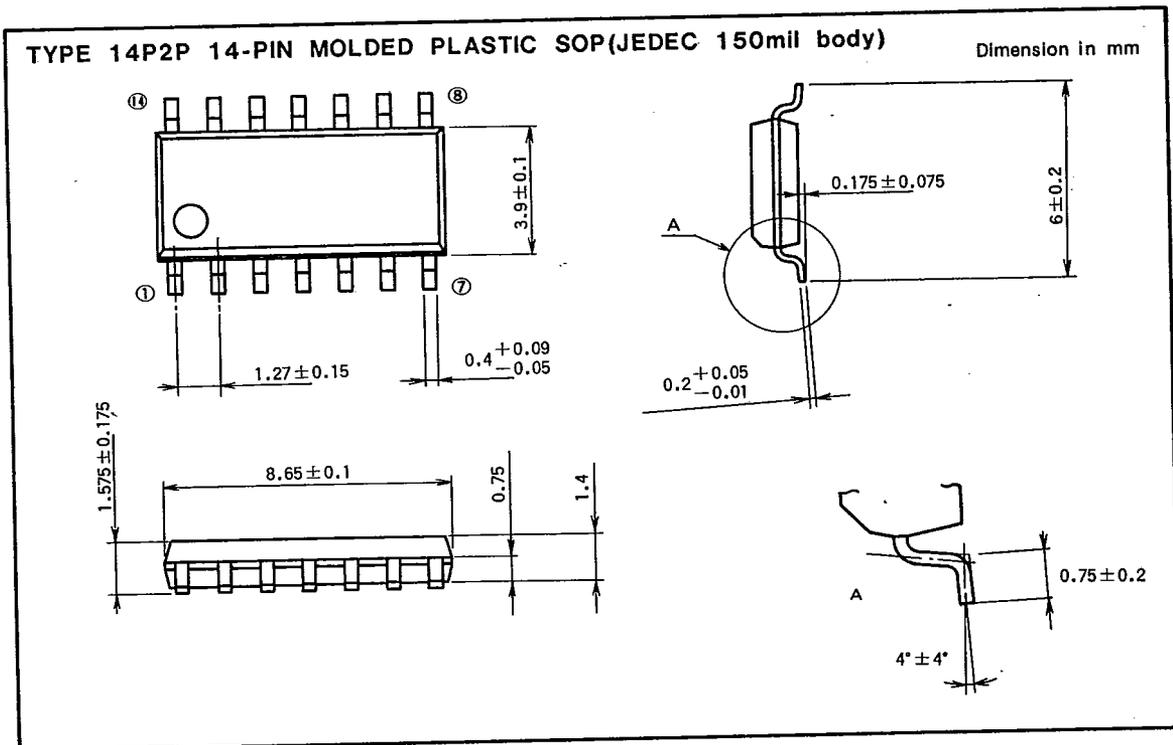
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91D 12854 D T-90-20

